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			04/15/2010	PAPER		

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | ALVARADO ET AL. | Examiner | David García Cervetti | 2436 | Page 1 of 4

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